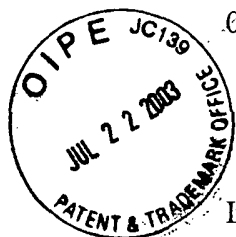


0500

03560.003310

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
TADASHI OKAMOTO ET AL. ) Examiner: Not Yet Assigned  
Application No.: 10/601,777 ) Group Art Unit: Not Yet Assigned  
Filed: June 24, 2003 )  
For: A METHOD FOR ACQUIRING )  
INFORMATION OF A BIOCHIP )  
USING TIME OF FLIGHT )  
SECONDARY ION MASS )  
SPECTROMETRY AND AN )  
APPARATUS FOR ACQUIRING )  
INFORMATION FOR THE )  
APPLICATION THEREOF : July 21, 2003

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents are also enclosed.

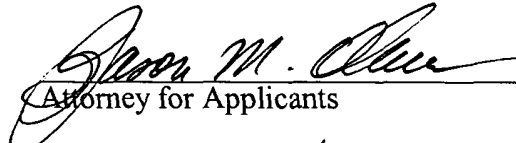
The concise explanation of relevance for the non-English documents may be found, inter alia, in the specification where they are cited and/or in the English language abstracts attached thereto. In addition, the concise explanation of relevance for JP11-187900 may be found in corresponding U.S. Patent No. 6,476,215 B1.

CONCLUSION

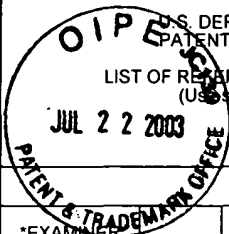
It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

  
\_\_\_\_\_  
Attorney for Applicants  
Registration No. 48,512

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FORM PTO 1449 (modified)		ATTY DOCKET NO. <b>03560.003310</b>		APPLICATION NO. <b>10/601,777</b>			
		APPLICANT <b>Tadashi Okamoto et al.</b>					
		FILING DATE <b>Jun 24, 2003</b>		GROUP <b>N.Y.A.</b>			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	<b>5,405,783</b>	<b>04/11/95</b>	<b>Pirrung et al.</b>	<b>436</b>	<b>518</b>		
	<b>5,601,980</b>	<b>02/11/97</b>	<b>Gordon et al.</b>	<b>435</b>	<b>6</b>		
	<b>6,384,237 B1</b>	<b>05/07/02</b>	<b>Suzuki et al.</b>	<b>549</b>	<b>13</b>		
	<b>6,476,215 B1</b>	<b>11/05/02</b>	<b>Okamoto et al.</b>	<b>536</b>	<b>25.3</b>		
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	<b>JP</b>	<b>11-187900</b>	<b>07/13/99</b>	<b>Japan</b>			<b>Abstract</b>
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	<b>Mark Schena et al., "Quantitative Monitoring of Gene Expression Patterns with a Complementary DNA Microarray," 270 Science 467-470 (October 1995).</b>						
	<b>H.F. Arlinghaus et al., "TOF-SIMS Characterization of DNA and PNA Biosensor Chips," Proceedings of the 12<sup>th</sup> International Conference on Secondary Ion Mass Spectrometry, pp. 951-954 (September 1999).</b>						
EXAMINER				DATE CONSIDERED			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.